

OIML CERTIFICATE OF CONFORMITY

Issuing authority

Name: NMI Certin B.V.
Address: Hugo de Grootplein 1
3314 EG Dordrecht
The Netherlands
Person responsible: Ing. C. Oosterman

Applicant

Name: Mettler-Toledo Inc.
Address: 1150 Dearborn Drive
Worthington, Ohio 43085
United States of America

Manufacturer of the certified type

Name: Mettler-Toledo (Changzhou) Precision Instrument Ltd.
Address: 5 Middle HuaShan Rd
XinBei District
ChangZhou JiangSu 213022 China

Identification of certified type

A digital compression load cell
Type : SLC820 ...
Fraction : $P_i = 0.8$
Temperature range -10 °C / 40 °C

For specifications, see page 2.

This Certificate attests the conformity of the above identified type (represented by the sample or samples identified in the associated Test Report, the test certificate and the description with number TC7579 and the appertaining documentation folder) with the requirements of the following Recommendation of the International Organization of Legal Metrology (OIML):

R60
Edition 2000 (E)
for accuracy class C



OIML Member state

The Netherlands

This Certificate relates only to the metrological and technical characteristics of the type of instrument covered by the relevant OIML Recommendation identified above.

This Certificate does not bestow any form of legal international approval.

The conformity was established by the results of tests and examinations provided in the associated

Test Report:

N° R60/2000-NL1-09.08 that includes 54 pages.

The Issuing Authority NL1

NMi Certin, 11 June 2009

C. Oosterman

Head Certification Board

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Load cell specifications:

Type	SLC820
Maximum capacity (E_{max})	20 000 kg up to and including 100 000 kg
Humidity Class	CH
Accuracy Class	C
Maximum number of load cell intervals (n)	6000
Ratio of minimum LC Verification interval $Y = E_{max} / V_{min}$	25 000

Important note: Apart from the mention of the Certificate's reference number and the name of the OIML Member State in which the Certificate is issued, partial quotation of the Certificate and of the associated Test Report is not permitted, although either may be reproduced in full.